



AC ЭНЕРГИЯ

Thyristor T453-800-36



Mean on-state current			I _{TAV}	800 A			
Repetitive peak off-state voltage			V _{DRM}	2400 - 3600 V			
Repetitive peak reverse voltage			V _{RRM}				
Turn-off time			t _q	400, 500 ms			
V _{DRM} , V _{RRM} , V	2400	2600	2800	3000	3200	3400	3600
Voltage code	24	26	28	30	32	34	36
T _j , °C	– 60 ÷ 125						

MAXIMUM ALLOWABLE RATINGS

Symbols and parameters		Units	Values	Test conditions	
ON-STATE					
I _{TAV}	Mean on-state current	A	800 1018	T _c =96 °C, Double side cooled T _c =85 °C, Double side cooled 180° half-sine wave; 50 Hz	
I _{TRMS}	RMS on-state current	A	1256	T _c =96 °C, Double side cooled 180° half-sine wave; 50 Hz	
I _{TSM}	Surge on-state current	kA	20.0 23.0	T _j =T _j _{max} T _j =25 °C	180° half-sine wave; t _p =10 ms; single pulse; V _D =V _R =0 V; Gate pulse: I _G =2 A; t _{GP} =50 ms; di _G /dt≥1 A/ms
			21.0 24.0	T _j =T _j _{max} T _j =25 °C	180° half-sine wave; t _p =8.3 ms; single pulse; V _D =V _R =0 V; Gate pulse: I _G =2 A; t _{GP} =50 ms; di _G /dt≥1 A/ms
I ² t	Safety factor	A ² s·10 ³	2000 2600	T _j =T _j _{max} T _j =25 °C	180° half-sine wave; t _p =10 ms; single pulse; V _D =V _R =0 V; Gate pulse: I _G =2 A; t _{GP} =50 ms; di _G /dt≥1 A/ms
			1800 2300	T _j =T _j _{max} T _j =25 °C	180° half-sine wave; t _p =8.3 ms; single pulse; V _D =V _R =0 V; Gate pulse: I _G =2 A; t _{GP} =50 ms; di _G /dt≥1 A/ms
BLOCKING					
V _{DRM} , V _{RRM}	Repetitive peak off-state and Repetitive peak reverse voltages	V	2400 - 3600	T _{j min} < T _j < T _j _{max} ; 180° half-sine wave; 50 Hz; Gate open	
V _{DSM} , V _{RSM}	Non-repetitive peak off-state and Non-repetitive peak reverse voltages	V	2500 - 3700	T _{j min} < T _j < T _j _{max} ; 180° half-sine wave; single pulse; Gate open	
V _D , V _R	Direct off-state and Direct reverse voltages	V	0.6·V _{DRM} 0.6·V _{RRM}	T _j =T _j _{max} ; Gate open	

TRIGGERING				
I_{FGM}	Peak forward gate current	A	8	$T_j=T_{j\max}$ $T_j=T_{j\max}$ for DC gate current
V_{RGM}	Peak reverse gate voltage	V	5	
P_G	Gate power dissipation	W	4	
SWITCHING				
$(di_G/dt)_{crit}$	Critical rate of rise of on-state current non-repetitive ($f=1$ Hz)	A/ms	1250	$T_j=T_{j\max}$; $V_D=0.67V_{DRM}$; $I_{TM}=4400$ A; Gate pulse: $I_G=2$ A; $t_{GP}=50$ ms; $di_G/dt \geq 2$ A/ms
THERMAL				
T_{stg}	Storage temperature	°C	-60...50	
T_j	Operating junction temperature	°C	-60...125	
MECHANICAL				
F	Mounting force	kN	24.0...28.0	
a	Acceleration	m/s ²	50	Device clamped

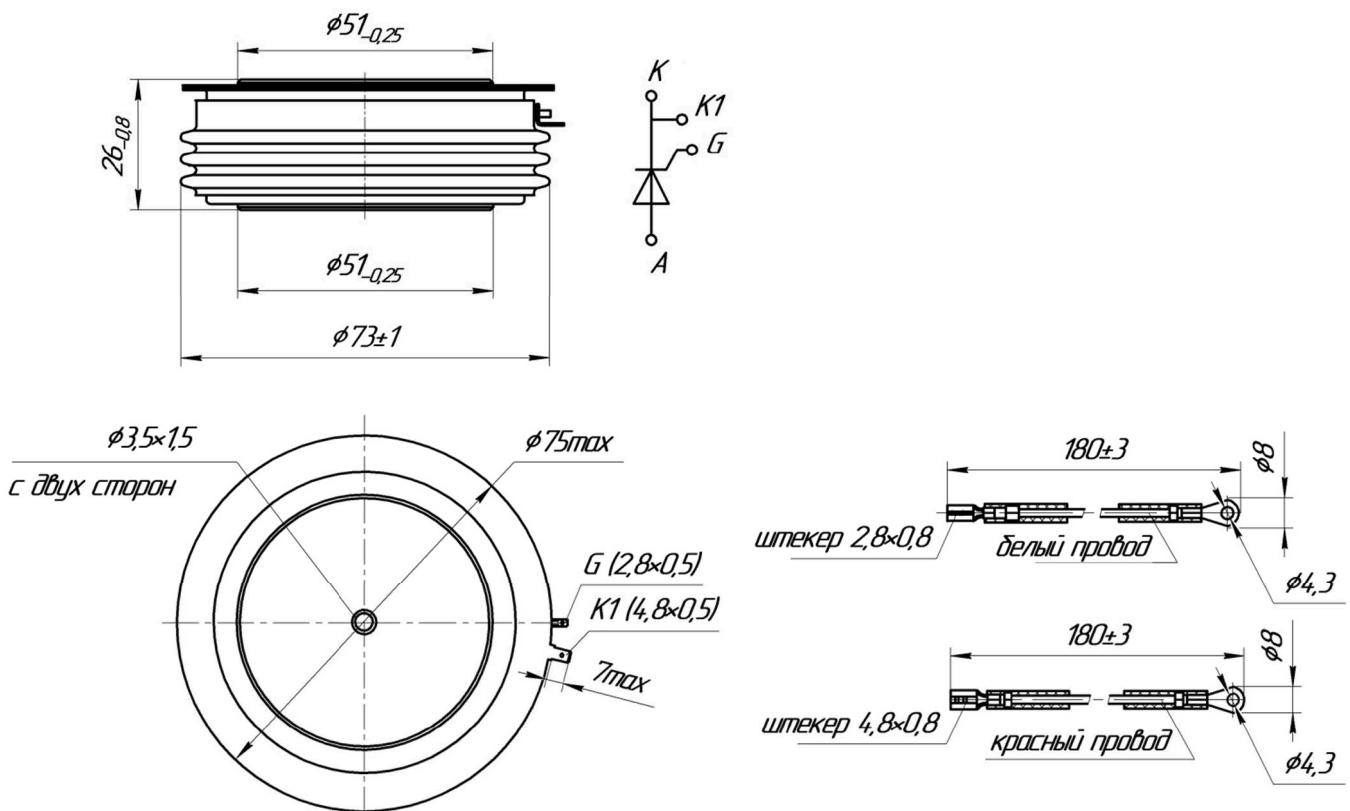
CHARACTERISTICS

Symbols and parameters		Units	Values	Conditions
ON-STATE				
V_{TM}	Peak on-state voltage, max	V	1.95	$T_j=25$ °C; $I_{TM}=2512$ A
$V_{T(TO)}$	On-state threshold voltage, max	V	1.078	$T_j=T_{j\max}$;
r_T	On-state slope resistance, max	mW	0.443	0.5 p $I_{TAV} < I_T < 1.5$ p I_{TAV}
I_L	Latching current, max	mA	1500	$T_j=25$ °C; $V_D=12$ V; Gate pulse: $I_G=2$ A; $t_{GP}=50$ ms; $di_G/dt \geq 1$ A/ms
I_H	Holding current, max	mA	300	$T_j=25$ °C; $V_D=12$ V; Gate open
BLOCKING				
I_{DRM}, I_{RRM}	Repetitive peak off-state and Repetitive peak reverse currents, max	mA	150	$T_j=T_{j\max}$; $V_D=V_{DRM}$; $V_R=V_{RRM}$
$(dv_D/dt)_{crit}$	Critical rate of rise of off-state voltage ¹⁾ , min	V/ms	200, 320, 500, 1000, 1600, 2000, 2500	$T_j=T_{j\max}$; $V_D=0.67V_{DRM}$; Gate open
TRIGGERING				
V_{GT}	Gate trigger direct voltage, max	V	3.00 2.50 1.50	$T_j=T_{j\min}$ $T_j=25$ °C $T_j=T_{j\max}$
I_{GT}	Gate trigger direct current, max	mA	500 300 150	$T_j=T_{j\min}$ $T_j=25$ °C $T_j=T_{j\max}$
V_{GD}	Gate non-trigger direct voltage, min	V	0.35	$T_j=T_{j\max}$;
I_{GD}	Gate non-trigger direct current, min	mA	65.00	$V_D=0.67V_{DRM}$; Direct gate current
SWITCHING				
t_{gd}	Delay time	ms	1.85	$T_j=25$ °C; $V_D=1500$ V; $I_{TM}=I_{TAV}$; $di/dt=200$ A/ms;
t_{gt}	Turn-on time, max	ms	7.00	Gate pulse: $I_G=2$ A; $V_G=20$ V; $t_{GP}=50$ ms; $di_G/dt=2$ A/ms
t_q	Turn-off time ²⁾ , max	ms	400, 500	$dv_D/dt=50$ V/ms; $T_j=T_{j\max}$; $I_{TM}=I_{TAV}$; $di_R/dt=-10$ A/ms; $V_R=100$ V; $V_D=0.67V_{DRM}$
Q_{rr}	Total recovered charge, max	mC	3000	$T_j=T_{j\max}$; $I_{TM}=I_{TAV}$; $di_R/dt=-5$ A/ms; $V_R=100$ V;
t_{rr}	Reverse recovery time, max	ms	50	
I_{rrM}	Peak reverse recovery current, max	A	120	

THERMAL					
R_{thjc}	Thermal resistance, junction to case, max	$^{\circ}\text{C}/\text{W}$	0.0180	Direct current	Double side cooled
R_{thjc-A}			0.0396		Anode side cooled
R_{thjc-K}			0.0324		Cathode side cooled
R_{thck}	Thermal resistance, case to heatsink, max	$^{\circ}\text{C}/\text{W}$	0.0040	Direct current	
MECHANICAL					
w	Weight, max	g	550		
D_s	Surface creepage distance	mm (inch)	31.60 (1.244)		
D_a	Air strike distance	mm (inch)	16.50 (0.649)		

OVERALL DIMENSIONS

Package type: PT53



K – cathode;

A – anode;

K1 – auxiliary cathode;

G – gate;

All dimensions in millimeters

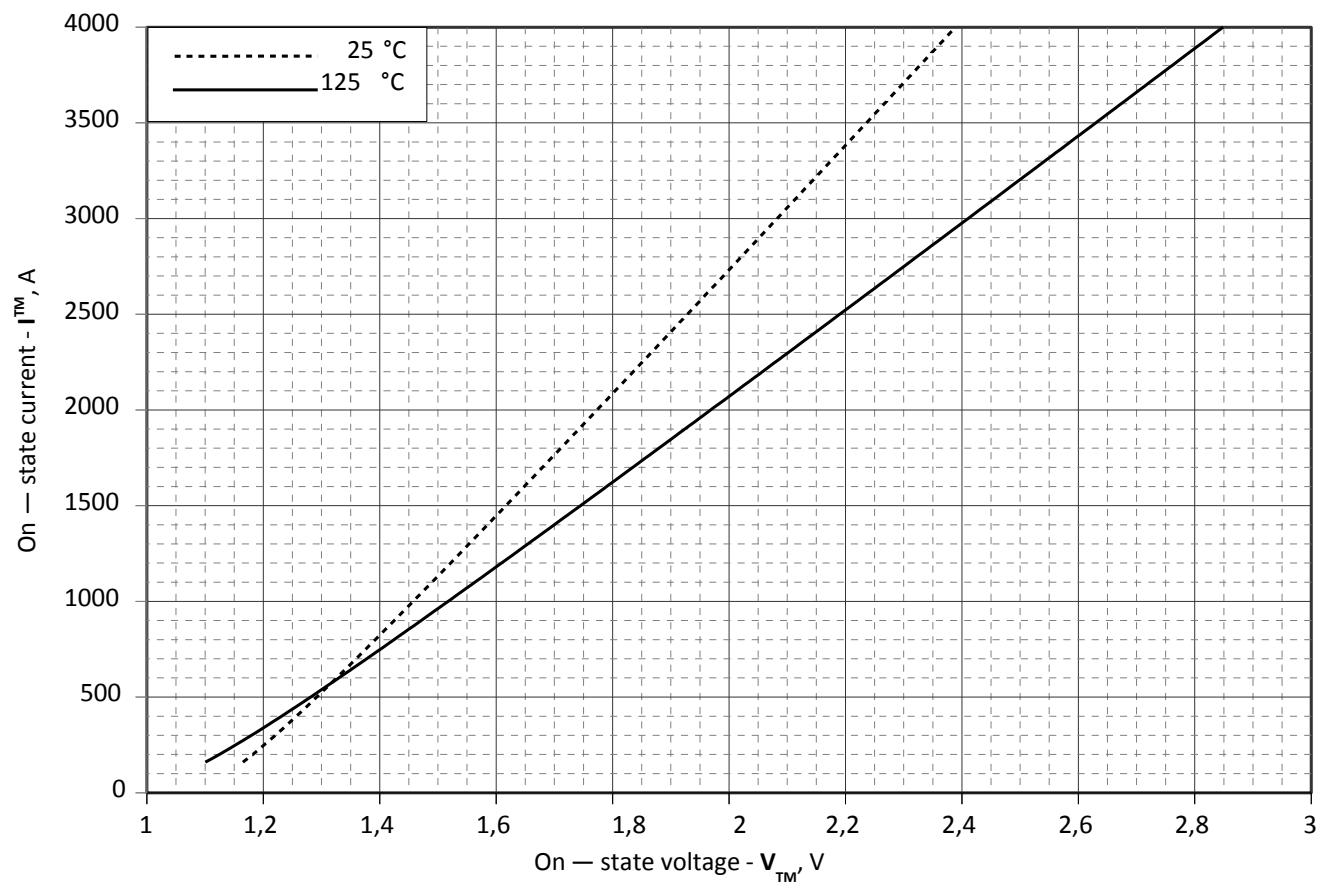


Fig 1 – On-state characteristics of Limit device

Analytical function for On-state characteristic:

$$V_T = A + B \cdot i_T + C \cdot \ln(i_T + 1) + D \cdot \sqrt{i_T}$$

	Coefficients for max curves	
	T _j = 25 °C	T _j = T _{j,max}
A	1.01230000	0.88100000
B	0.00029817	0.00042769
C	0.01989900	0.02908500
D	0.00030044	0.00024764

On-state characteristic model (see Fig. 1)

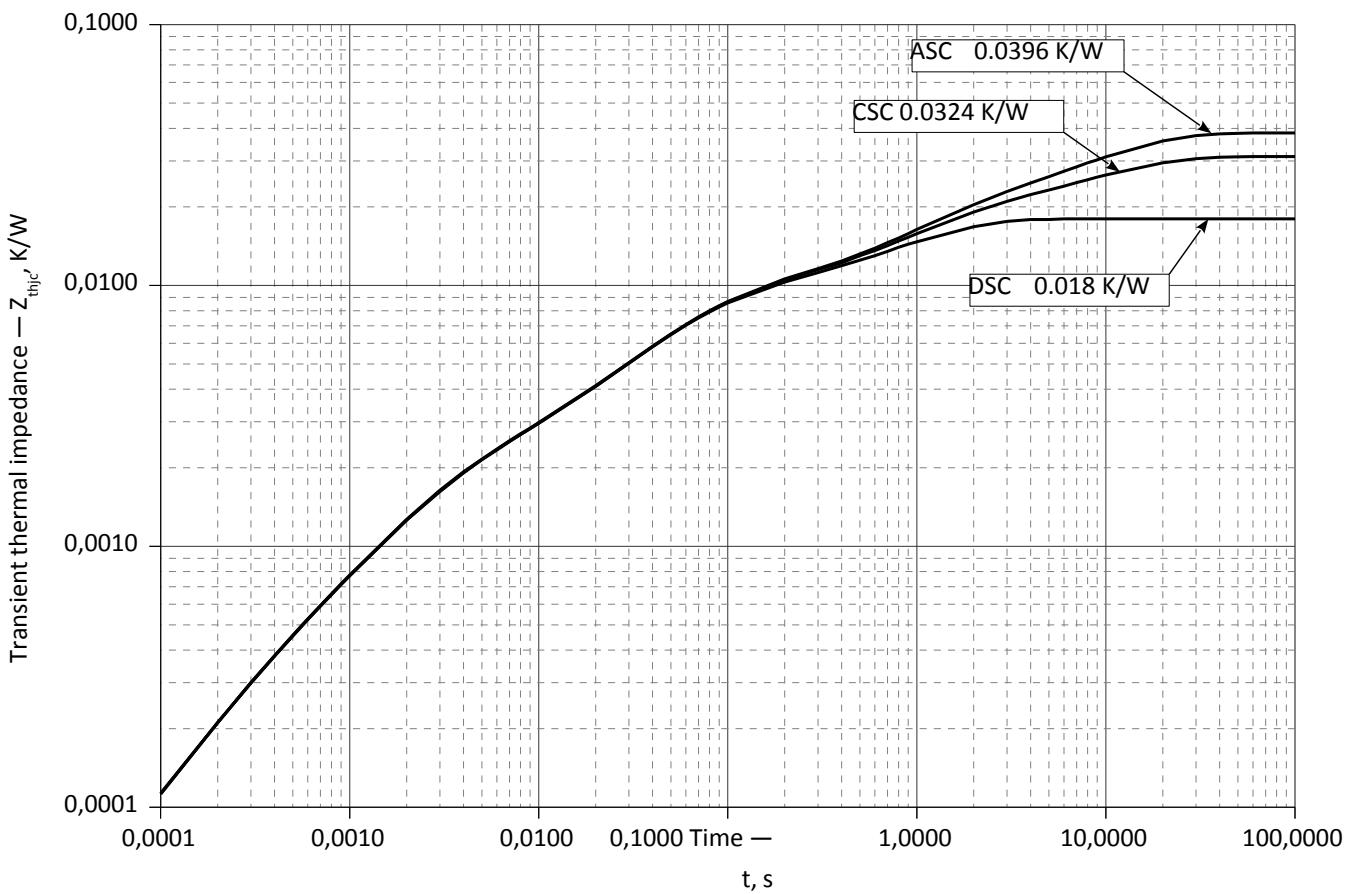


Fig 2 – Transient thermal impedance Z_{thjc} vs. time t

Analytical function for Transient thermal impedance junction to case Z_{thjc} for DC:

$$Z_{thjc} = \sum_{i=1}^n R_i \left(1 - e^{-\frac{t}{\tau_i}} \right)$$

Where $i = 1$ to n , n is the number of terms in the series.

t = Duration of heating pulse in seconds. Z_{thjc}

= Thermal resistance at time t .

R_i = Amplitude of p_{th} term.

τ_i = Time constant of r_{th} term.

DC Double side cooled

i	1	2	3	4	5	6
R_i , K/W	0.009241	0.006037	0.001231	0.001054	0.0003396	0.00009575
τ_i , s	0.9673	0.04967	0.002733	0.07734	0.001638	0.0002248

DC Anode side cooled

i	1	2	3	4	5	6
R_i , K/W	0.01318	0.009281	0.006055	0.001018	0.001535	0.0001182
τ_i , s	9.745	1.028	0.05591	0.03732	0.002468	0.0002687

DC Cathode side cooled

i	1	2	3	4	5	6
R_i , K/W	0.02041	0.009325	0.006949	0.0001252	0.001516	0.0001119
τ_i , s	9.752	1.065	0.05344	0.01407	0.002421	0.0002554

Transient thermal impedance junction to case Z_{thjc} model (see Fig. 2)

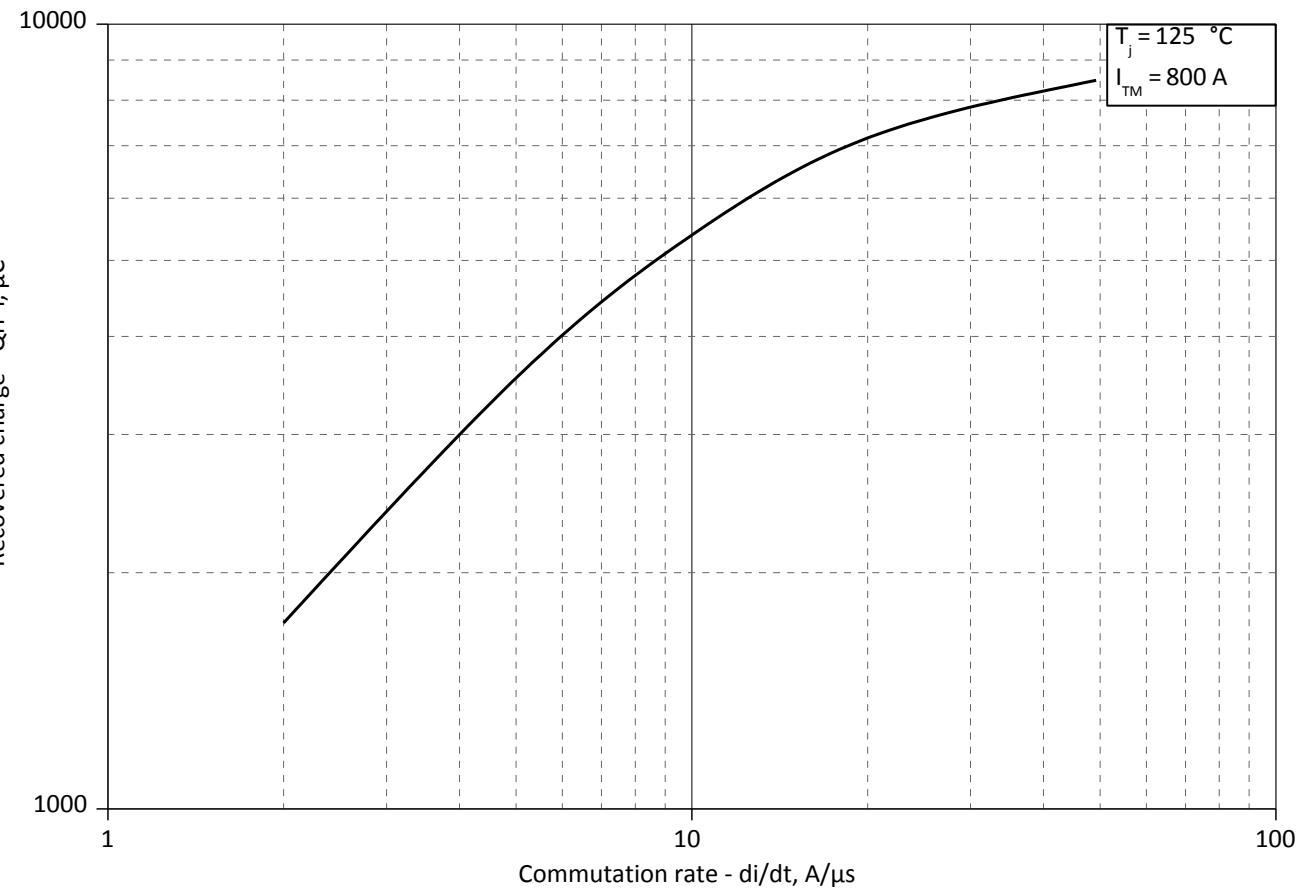


Fig 3 – Maximum recovered charge Q_{rr-i} (integral) vs. commutation rate di_R/dt

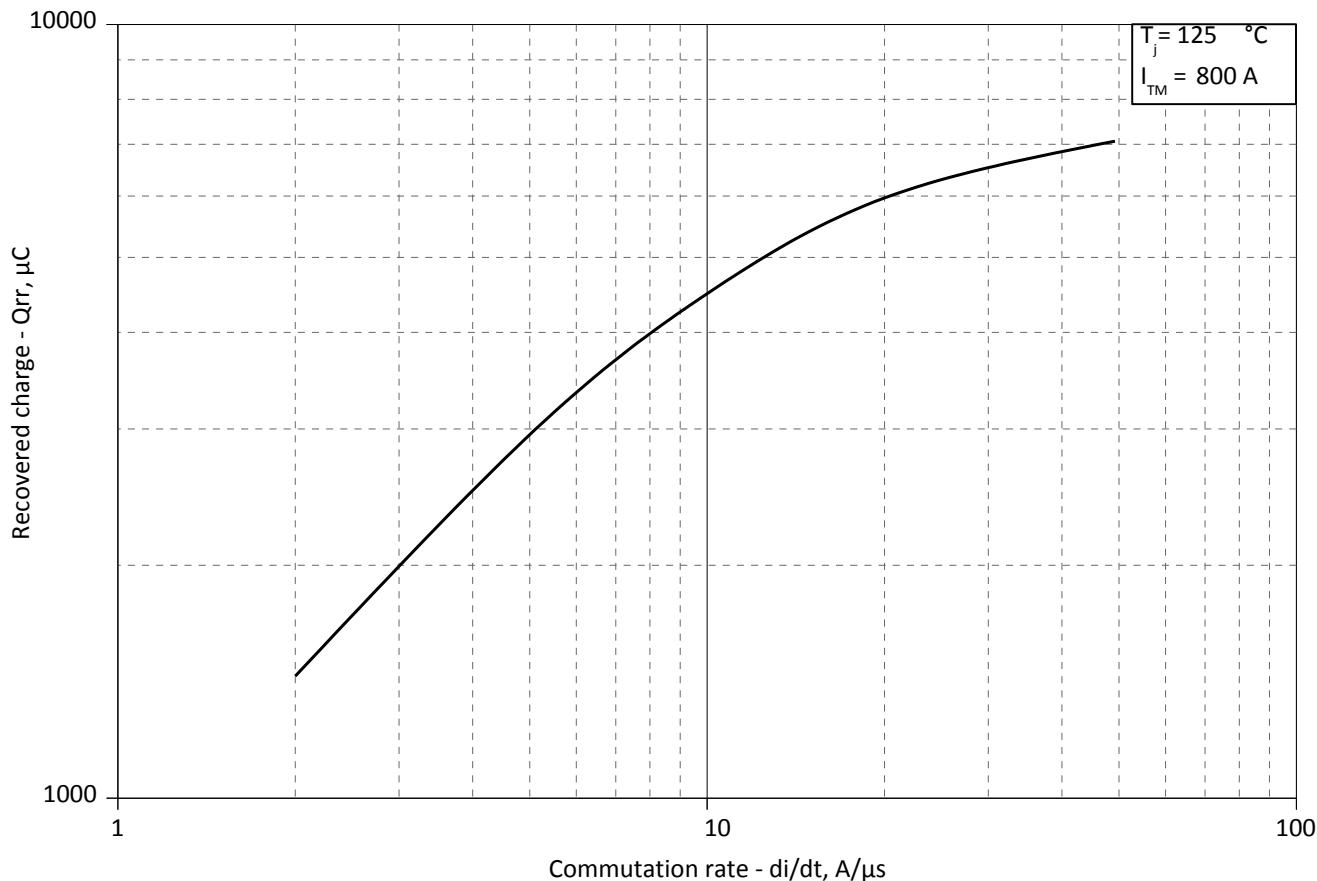


Fig 4 – Maximum recovered charge Q_{rr} vs. commutation rate di_R/dt (25% chord)

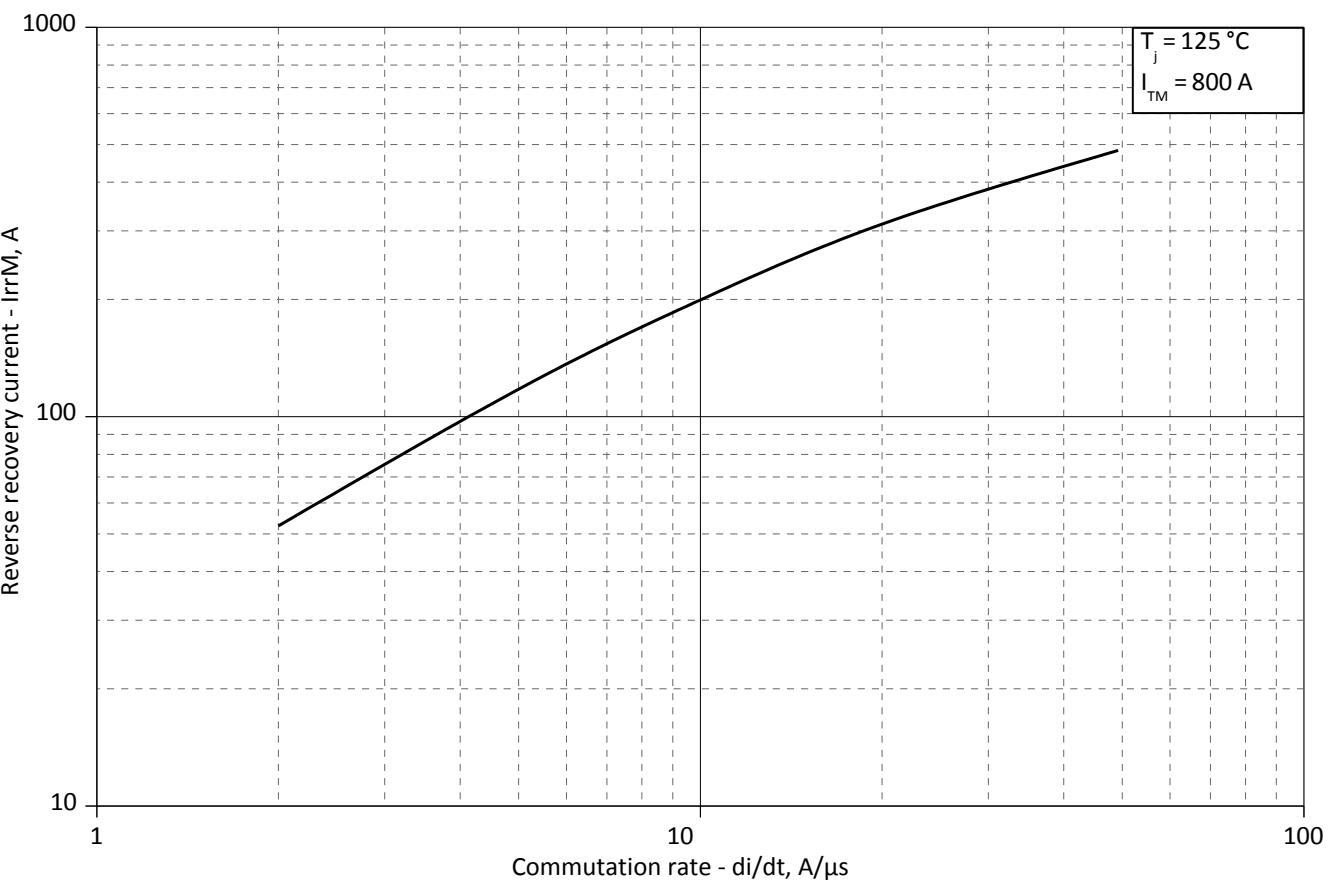


Fig 5 – Maximum reverse recovery current I_{rrM} vs. commutation rate di_R/dt

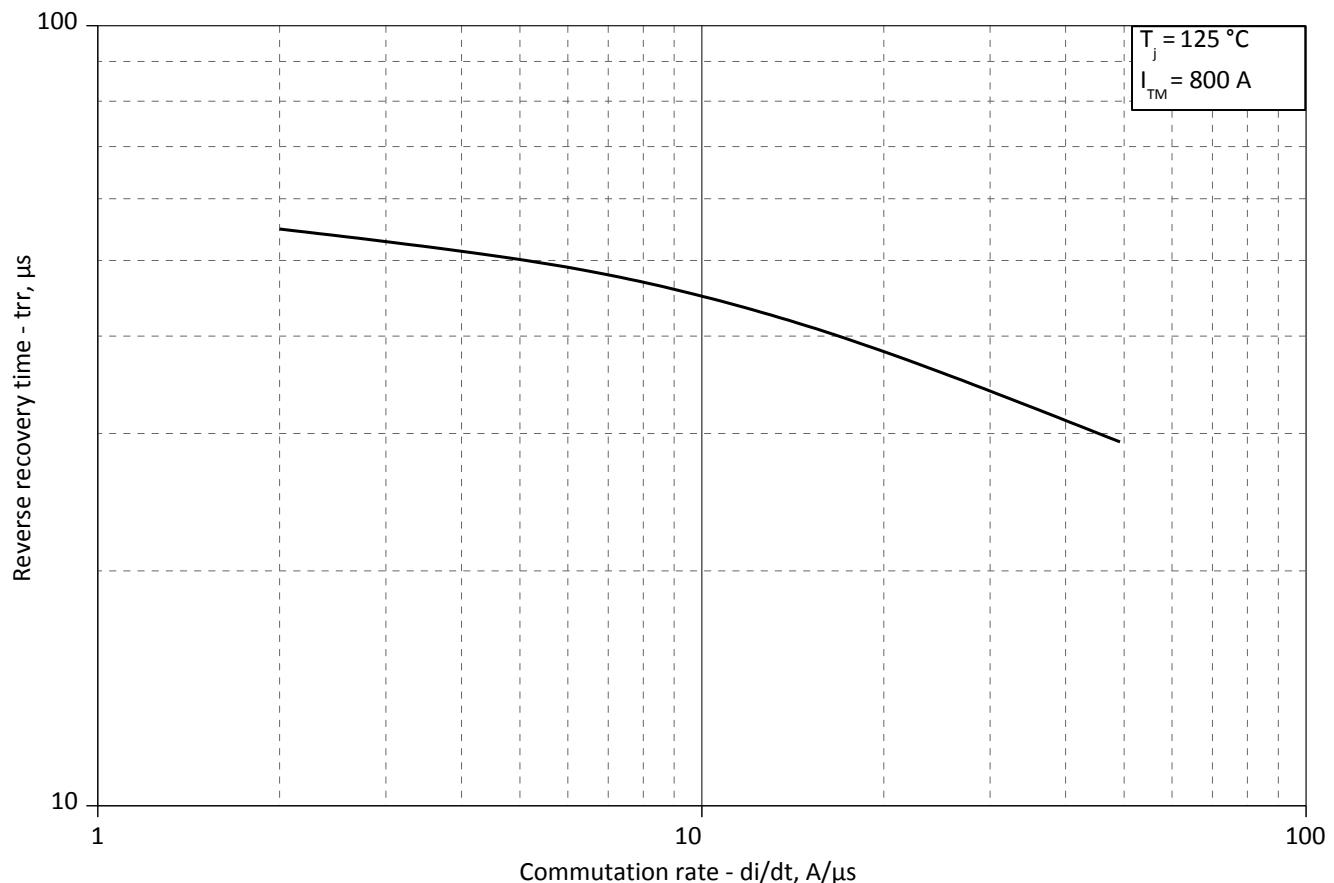


Fig 6 – Maximum recovery time t_{rr} vs. commutation rate di_R/dt (25% chord)

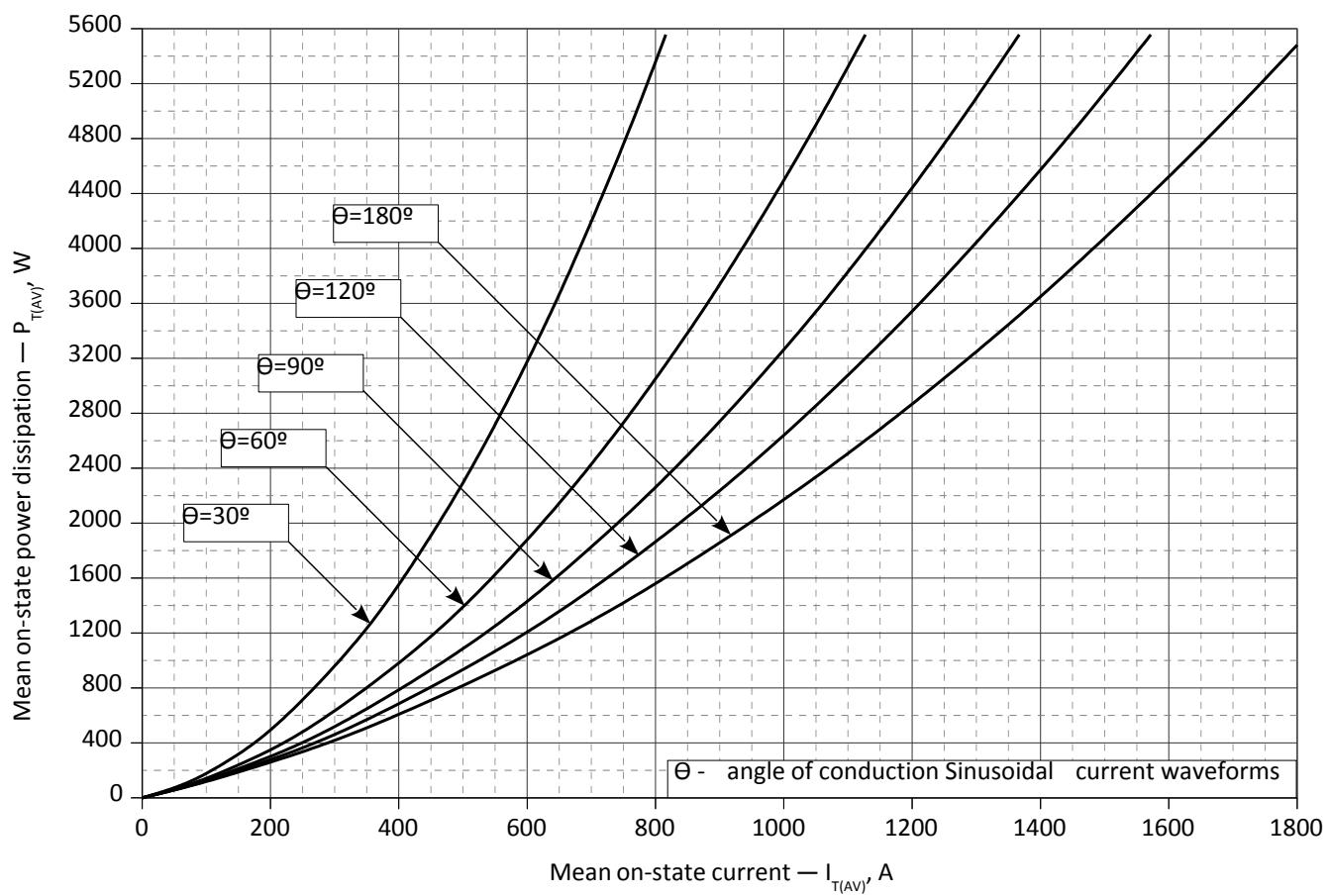


Fig. 7 - Mean on-state power dissipation P_{TAV} vs. mean on-state current I_{TAV} for sinusoidal current waveforms at different conduction angles (f=50Hz, DSC)

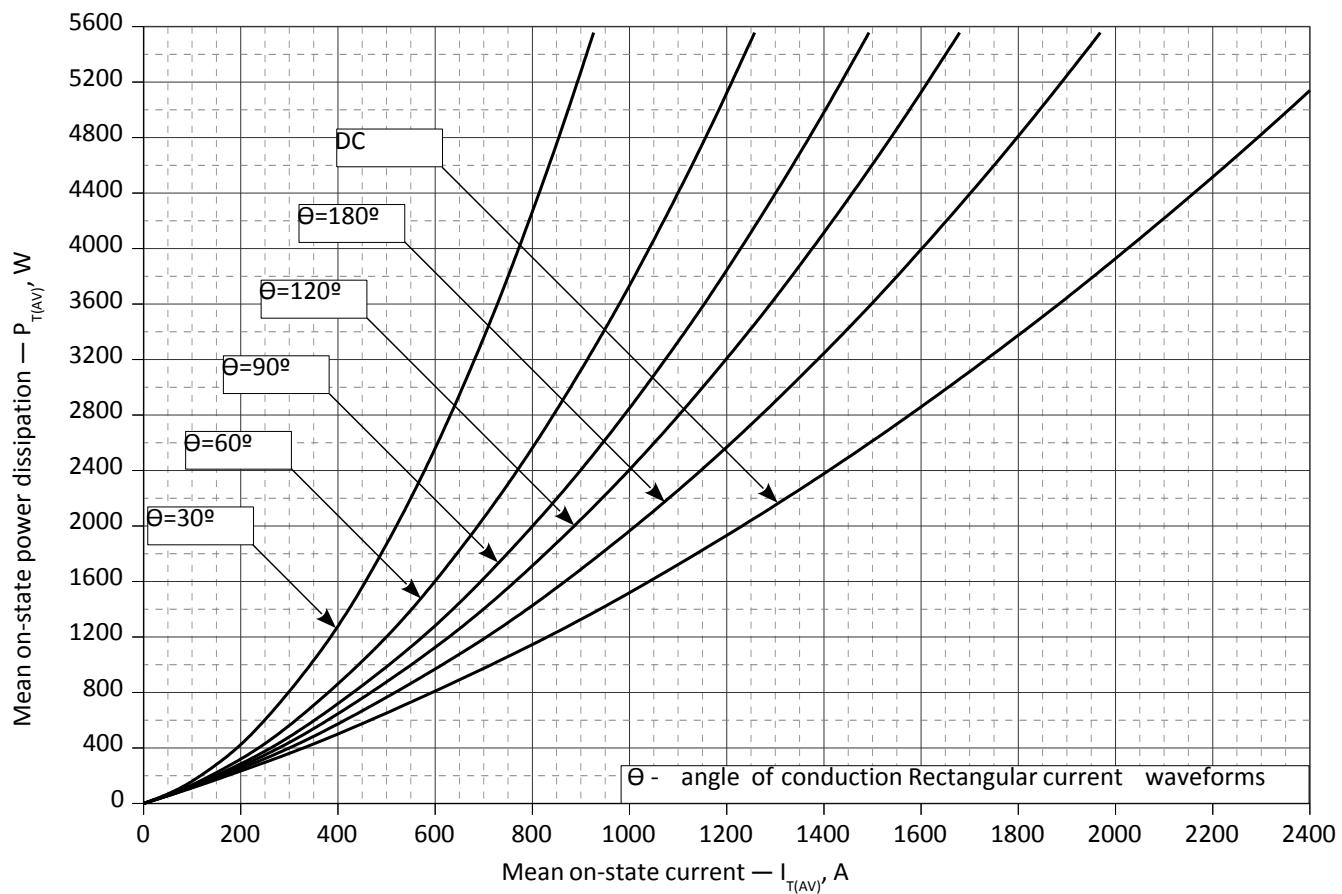


Fig. 8 – Mean on-state power dissipation P_{TAV} vs. mean on-state current I_{TAV} for rectangular current waveforms at different conduction angles and for DC (f=50Hz, DSC)

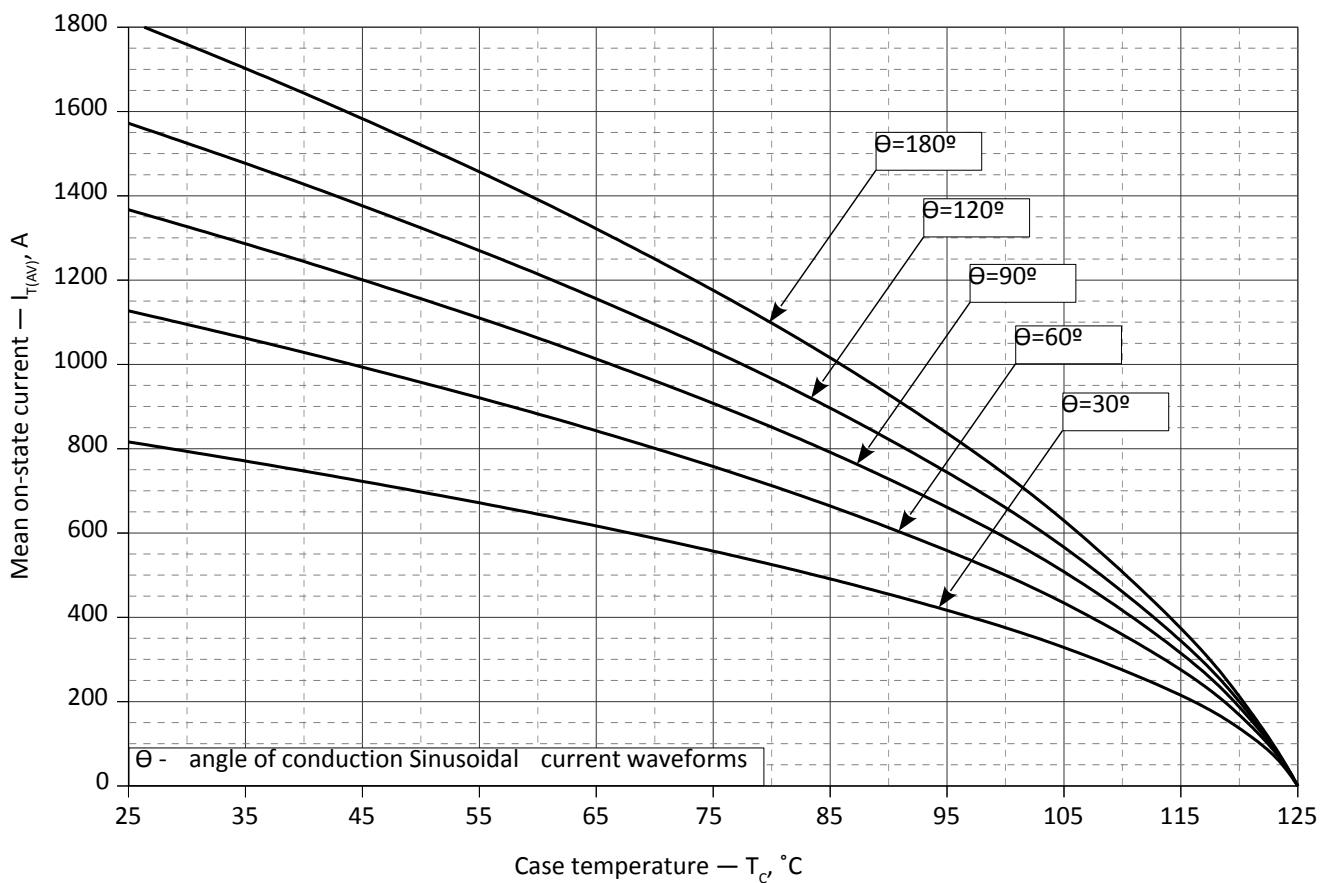


Fig. 9 – Mean on-state current I_{TAV} vs. case temperature T_c for sinusoidal current waveforms at different conduction angles (f=50Hz, DSC)

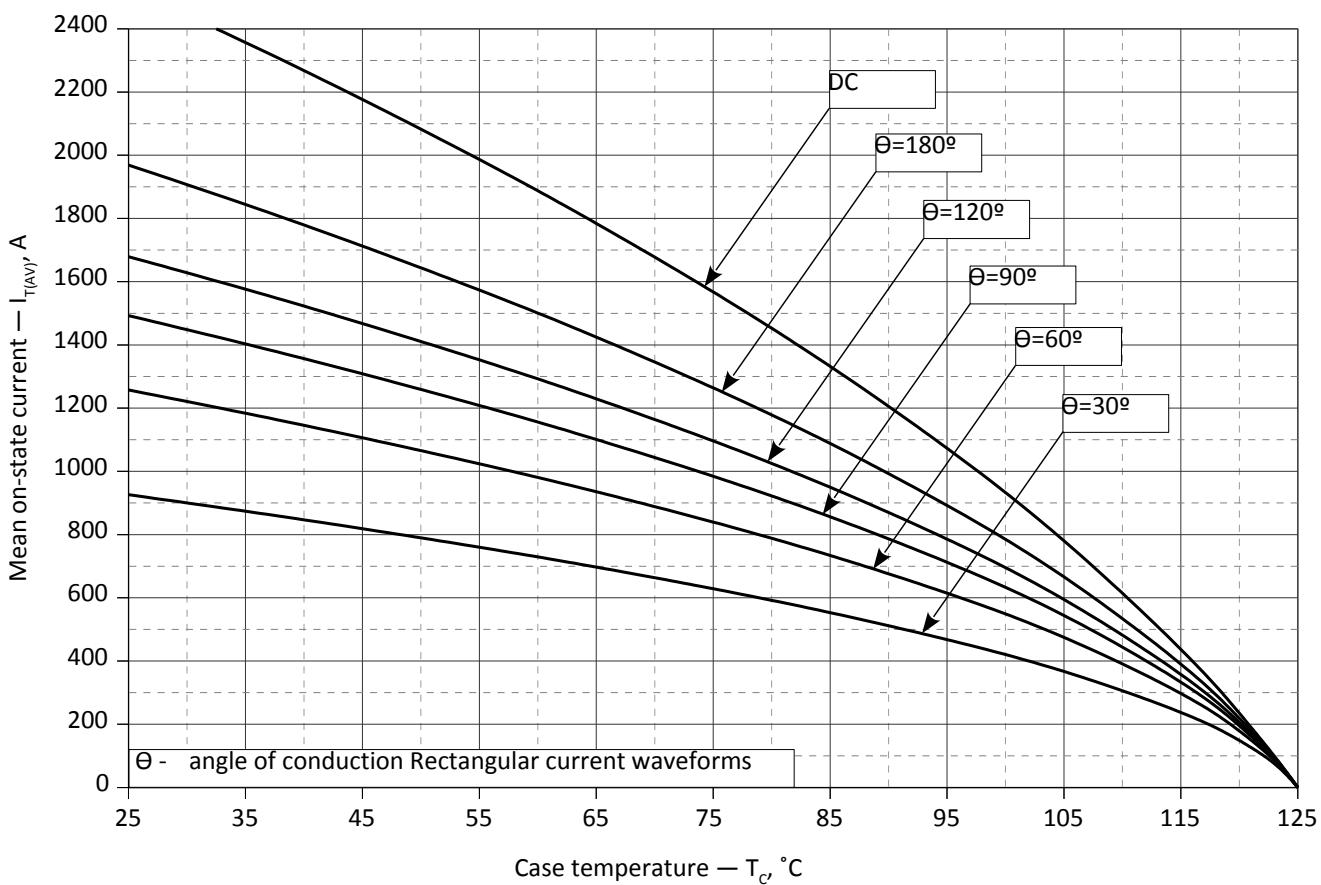


Fig. 10 - Mean on-state current I_{TAV} vs. case temperature T_c for rectangular current waveforms at different conduction angles and for DC (f=50Hz, DSC)

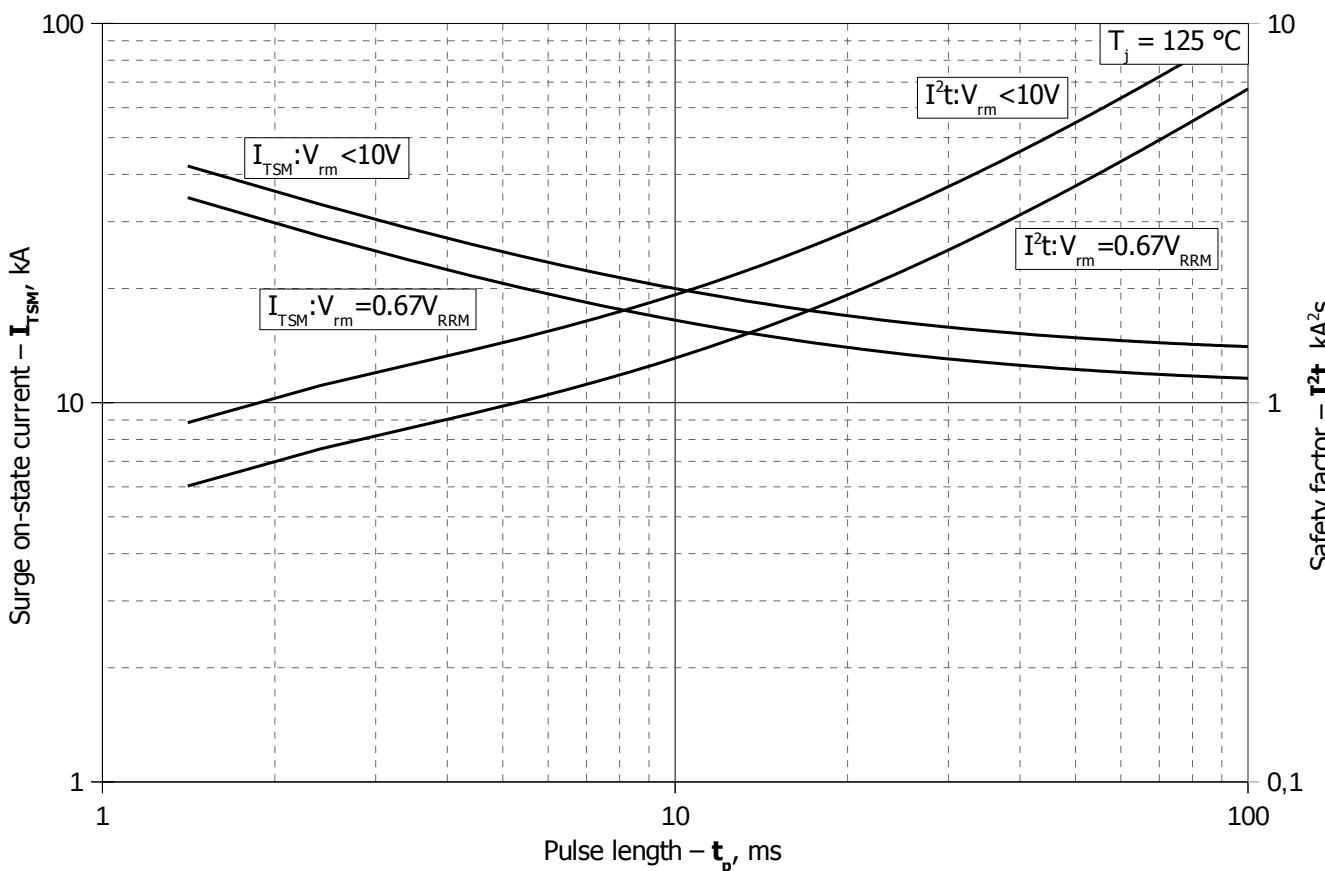


Fig. 11 – Maximum surge on-state current I_{TSM} and safety factor I^2t vs. pulse length

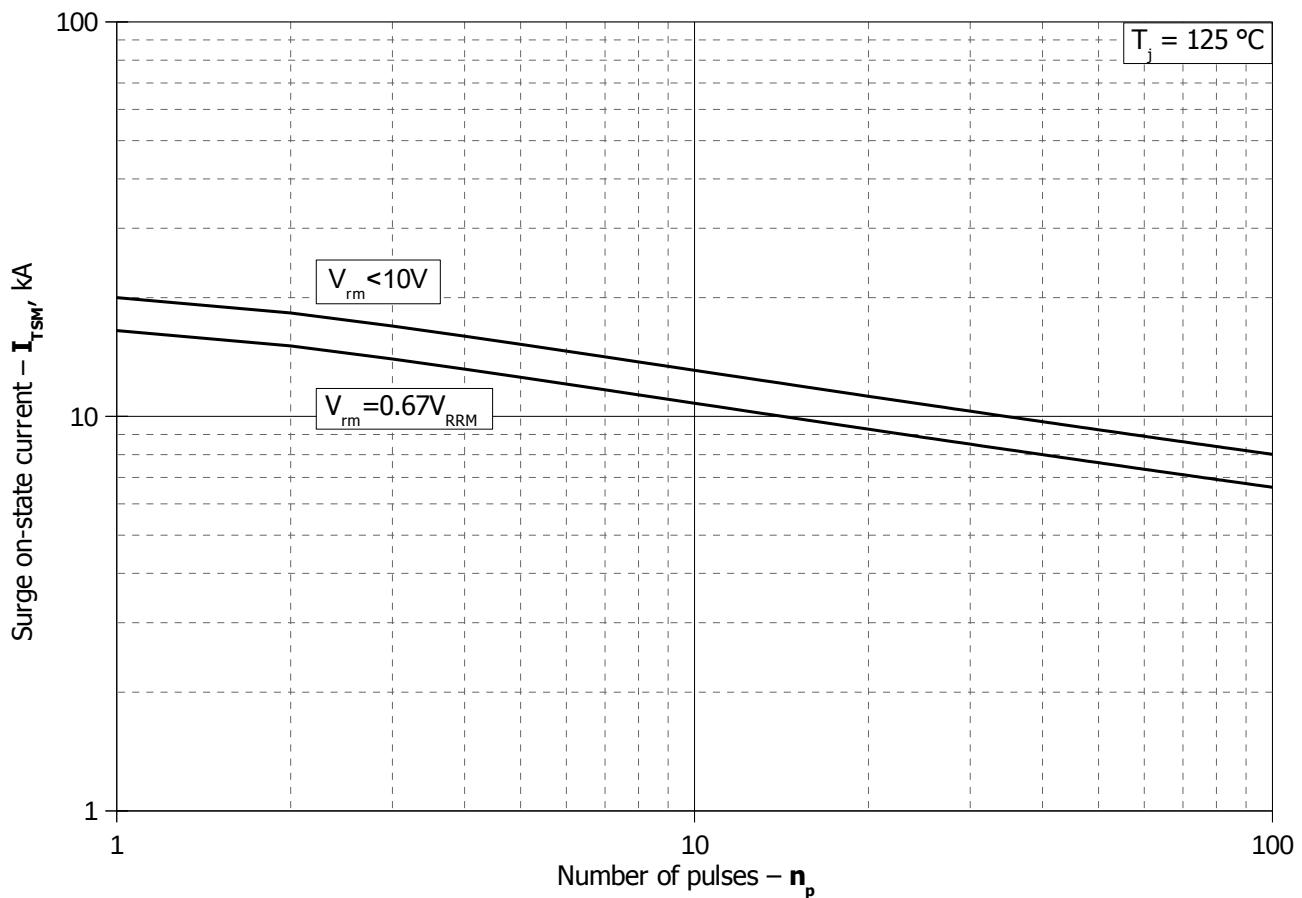


Fig. 12 - Maximum surge on-state current I_{TSM} vs. number of pulses